

Search Notes

Application/Control No.

10/724,119

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under
Reexamination

CHO ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	51	3/1/2005	PN
	282		
	285		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
330	51	3/5/2005	PN
	282		
	285		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR